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17b ABSTRACT (Continue on reverse if necessary and identify by block number)

This report describes a mathematical framework for segmenting scenes and for detecting the presence of distinguished objects. In digital images can be based on classical principles of statistical inference if appropriate mathematical models are developed for observable pictures. The main goal of this research was to devise and analyze alternative image models for digitized FLIR images. This work has been done in close cooperation with the Advanced Modeling Team of the U.S. Army Night Vision and Electro-Optics Laboratory, Ft. Belvoir, Virginia. This report describes hierarchical Markov Random Field models and their application to segmentation and detection of FLIR images.

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**Image Modeling:
A Mathematical Framework for Segmentation
and Object Detection**

FINAL TECHNICAL REPORT

Donald Geman
Stuart Geman
Ulf Grenander
Donald E. McClure

20 March 1987

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Statistical Consulting Associates, Inc.
P.O. Box 2476 (148 Waterman Street)
Providence, Rhode Island 02906-0476

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Abstract

Decision rules for segmenting scenes and for detecting the presence of distinguished objects in digital images can be based on classical principles of statistical inference if appropriate mathematical models are developed for observable pictures. The main goal of this research was to devise and analyze alternative image models for digitized FLIR images. The work has been done in close cooperation with the Advanced Modeling Team of the U.S. Army Night Vision and Electro-Optics Laboratory, Ft. Belvoir, Virginia. This report concentrates on hierarchical Markov Random Field models and their application to restoration and segmentation of FLIR images.

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Contents

1 INTRODUCTION.	3
2 BAYESIAN PARADIGM.	5
2.1 Image Models.	5
2.2 Degradation Model.	7
2.3 Posterior Distribution.	8
2.4 MAP Estimate.	9
2.5 Computing.	10
3 A GENERIC OBJECT/BACKGROUND MODEL.	13
3.1 Scene Model.	13
3.2 Degradations.	16
4 IMPLEMENTATION OF THE RESTORATION ALGORITHM.	18
4.1 Main Program RESTOR.	18
4.2 Include File COMMON.	20
4.3 Subroutine READIN.	21
4.4 Subroutine WRITEO.	25
4.5 Subroutine ITXP.	26
4.6 Subroutine PIXEN.	28
4.7 Subroutine PIXENO.	30
4.8 Subroutine ITXE.	31
4.9 Subroutine DEE.	32
4.10 Function Subprogram GGUBFS.	37
5 FLIR EXAMPLES.	39
6 REFERENCES.	40
A COMPLEX SYSTEMS WORKING PAPERS.	42
B FIGURES.	44

1 INTRODUCTION.

Our primary goal has been to construct a mathematical foundation for the rational choice of decision functions for image analysis. This has included structured models for the background against which certain objects, such as tanks, trucks, or armored personnel carriers, appear. The backgrounds are "complex" in that their composition is highly variable and cannot be known in advance. The objects are "simple" in that they can be characterized by a small number of parameters. While the emphasis has been placed on the logical and mathematical foundations, considerable effort has been given to the construction of algorithms. It is important to keep the algorithmic issues in mind so that we arrive at decision procedures that work and that can be computed with reasonable resources.

This report focuses on a strategy for image modeling that has been developed for a number of practical settings. Here we develop it for the analysis of FLIR images. Indeed, this project—while it is immediately concerned with problems suggested by the U.S. Army Night Vision and Electro-Optics Laboratory—has had a tremendous impact on the development of a general Bayesian methodology for automatic analysis of digital images. Today that methodology is successfully addressing practical problems in medical imaging (computed tomography, ultrasound), remote sensing (interpretation of SAR images), automatic inspection (analysis of textured optical images of silicon wafers), and image understanding (optical character recognition, boundary finding, segmentation).

In the interest of presenting a self-contained and coherent report on mathematical models for FLIR images, we shall concentrate this paper on the general Bayesian model and its adaptation to FLIR imagery. Our interactions with the Advanced Modeling Team at NV&EOL have had many other facets, including frequent on-site working sessions, supervision of the development of computer algorithms, direction for the formation of a data base of features of FLIR images, statistical analyses, and assistance with providing information on other mathematical modeling efforts. These interactions are all directly related to the overall project on image modeling, and are documented elsewhere. In particular, the internal working memoranda listed in Appendix A provide additional details on both theoretical and practical aspects of the effort.

Section 2 of this paper gives an overview and basic examples of the Bayesian modeling strategy. It covers the range of issues from specification of the probabilistic framework to the design of computational algorithms.

Section 3 describes the adaptation of the general Bayesian paradigm to digitized FLIR images. Here we describe a specific hierarchical probabilistic model which is useful for FLIR image restoration and segmentation.

Section 4 presents a FORTRAN implementation of the image restoration algorithm.

Program listings are included.

Section 5 briefly describes the application of the restoration algorithm to eight examples of FLIR images provided to us by NV&EOL.

Finally, two appendices include, respectively, (i) a list of internal working papers developed during the project and previously shared with the Advanced Modeling Team at NV&EOL and (ii) pictures illustrating the examples cited in Section 5.

We gratefully acknowledge the contributions made to this research effort by Frank Shields and Vince Mirelli of the Advanced Modeling Team at NV&EOL. The discussions of the fundamental mathematical issues with Dr. Mirelli have provided a tremendous stimulus for focusing our efforts on meaningful ways of bringing mathematics to bear on challenging practical problems.

2 BAYESIAN PARADIGM.

In real scenes, neighboring pixels typically have similar intensities, boundaries are usually smooth and often straight, textures, although sometimes random locally, define spatially homogeneous regions, and objects, such as grass, tree trunks, branches and leaves, have preferred relations and orientations. Our approach to picture processing is to articulate such regularities mathematically, and then to exploit them in a statistical framework to make inferences. The regularities are rarely deterministic; instead, they describe correlations and likelihoods. This leads us to the Bayesian formulation, in which prior expectations are formally represented by a probability distribution. Thus we design a distribution (a "prior") on relevant scene attributes to capture the tendencies and constraints that characterize the scenes of interest. Picture processing is then guided by this prior distribution, which, if properly conceived, enormously limits the plausible restorations and interpretations.

The approach involves five steps, which we shall briefly review here (see [4] and [9] for more details). This will define the general framework, and then, in the following sections, we will concentrate on the analysis of samples of FLIR images, as an illustrative application.

2.1 Image Models.

These are probability distributions on relevant image attributes. Both for reasons of mathematical and computational convenience, we use *Markov random fields* (MRF) as prior probability distributions. Let us suppose that we index all of the relevant attributes by the index set S . S is application specific. It typically includes indices for each of the pixels (about 512x512 in the usual video digitization) and may have other indices for such attributes as boundary elements, texture labels, object labels and so-on. Associated with each "site" $s \in S$ is a real-valued random variable X_s , representing the state of the corresponding attribute. Thus X_s may be the measured intensity at pixel s (typically, $X_s \in \{0, \dots, 255\}$), or simply 1 or 0 as a boundary element at location s is present or absent.

The kind of knowledge we represent by the prior distribution is usually "local," which is to say that we articulate regularities in terms of small local collections of variables. In the end, this leads to a distribution on $X = \{X_s\}_{s \in S}$ with a more or less "local neighborhood structure" (again, we refer to [4] and [9] for details). Specifically, our priors are Markov random fields: there exists a (symmetric) *neighborhood relation* $G = \{G_s\}_{s \in S}$, wherein $G_s \subseteq S$ is the set of neighbors of s , such that

$$\Pi(X_s = x_s | X_r = x_r, r \in S, r \neq s) = \Pi(X_s = x_s | X_r = x_r, r \in G_s)$$

$\Pi(a|b)$ is conditional probability, and, by convention, $s \notin G_s$. G symmetric means $s \in G_r \Leftrightarrow r \in G_s$. (Here, we assume that the range of the random vector X is discrete; there are obvious modifications for the continuous or mixed case.)

It is well-known, and very convenient, that a distribution Π defines a MRF on S with neighborhood relation G if and only if it is Gibbs with respect to the same graph, (S, G) . The latter means that Π has the representation

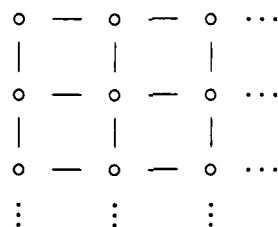
$$(2.1) \quad \Pi(x) = \frac{1}{z} e^{-U(x)}$$

where

$$(2.2) \quad U(x) = \sum_{c \in C} V_c(x)$$

C is the collection of all cliques in (S, G) (collections of sites such that every two sites are neighbors), and $V_c(x)$ is a function depending only on $\{x_s\}_{s \in c}$. U is known as the "energy," and has the intuitive property that the low energy states are the more likely states under Π . The normalizing constant, z , is known as the "partition function". The Gibbs distribution arises in statistical mechanics as the equilibrium distribution of a system with energy function U .

As a simple example (too simple to be of much use for real pictures) suppose the pixel intensities are known, a priori, to be one of two levels, minus one ("black") or plus one ("white"). Let S be the $N \times N$ square lattice, and let G be the neighborhood system that corresponds to nearest horizontal and vertical neighbors:



For picture processing, think of N as typically 512. Suppose that the only relevant regularity is that neighboring pixels tend to have the same intensities. An "energy" consistent with this regularity is the "Ising" potential:

$$U(x) = -\beta \sum_{(s,t)} x_s x_t \quad \beta > 0$$

where $\sum_{(s,t)}$ means summation over all neighboring pairs $s, t \in S$. The minimum of U is achieved when $x_s = x_t \quad \forall s, t \in S$. Under (2.1), the likely pictures are therefore the ones

that respect our prior expectations; they segment into regions of constant intensities. The larger β , the larger the typical region. Later we will discuss the issue of *estimating* model parameters such as β . (With energy (2.2), Π in (2.1) is called the Ising model. It models the equilibrium distribution of the spin states of the atoms in a ferromagnet. These spins tend to “line up,” and hence the favored configurations contain connected regions of constant spins.)

One very good reason for using MRF priors is their Gibbs representations. Gibbs distributions are characterized by their energy functions, and these are more convenient and intuitive for modelling than working directly with probabilities. See, for example, [3], [4], [5], [9], and [13] for many more examples, and Section 3 below for a more complex and useful MRF model.

2.2 Degradation Model.

The image model is a distribution $\Pi(\cdot)$ on the vector of image attributes $X = \{X_s\}_{s \in S}$. *By design*, the components of this vector contain all of the relevant information for the image processing task at hand. Hence, the goal is to estimate X . This estimation will be based upon partial or corrupted observations, and based upon the prior information. In emission tomography, X represents the spatial distribution of isotope in a target region of the body. What is actually observed is a collection of photon counts whose probability law is Poisson, with a mean function that is an attenuated radon transform of X . In the texture labelling problem, X is the pixel intensity array and a corresponding array of texture labels. Each label gives the texture type of the associated pixel. The observation is only partial: we observe the pixels, which are just the digitized picture, but not the labels. The purpose is then to estimate the labels from the picture. In a generic model for FLIR images described in Section 3, X is a hierarchical model built from the pixel intensity array and from a superimposed array of unobservable edge elements. Again, the observation is only partial: we observe the pixels, degraded as they are by atmospheric effects and the sensor, but not the edge elements that are combined to form boundaries between objects and background. A purpose of image segmentation is to estimate the boundaries from the observed picture.

The observations are related to the image process (X) by a *degradation model*. This models the relation between X and the *observation process*, say $Y = \{Y_s\}_{s \in T}$. For texture analysis, we will define $X = (X^P, X^L)$, where X^P is the usual grey-level pixel intensity process, and X^L is an associated array of texture labels. The observed picture is just X^P , and hence $Y = X^P$: the degradation is a projection. More typically, the degradation involves a random component, as in the tomography setting where the observations are Poisson variables whose means are related to the image process X . A more simple, and

widely studied (if unrealistic) example is additive “white” noise. Let $X = \{X_s\}_{s \in S}$ be just the basic pixel process. In this case, $T = S$, and for each $s \in S$ we observe

$$Y_s = X_s + \eta_s$$

where, for example, $\{\eta_s\}_{s \in S}$ is Gaussian with independent components, having means 0 and variances σ^2 .

Formally, the degradation model is a conditional probability distribution, or density, for Y given X : $\Pi(y|x)$. If the degradation is just added “white noise,” as in the above example, then

$$\Pi(y|x) = \left(\frac{1}{2\pi\sigma^2}\right)^{\frac{|S|}{2}} \exp\left\{-\frac{1}{2\sigma^2} \sum_{s \in S} (y_s - x_s)^2\right\}$$

For labelling textures, the degradation is deterministic: $\Pi(y|x)$ is concentrated on $y = x^P$, where $x = (x^P, x^L)$ has both pixel and label components.

2.3 Posterior Distribution.

This is the conditional distribution on the image process X given the observation process Y . This “posterior” or “*a posteriori*” distribution contains the information relevant to the image restoration or image analysis task. Given an observation $Y = y$, and assuming the image model ($\Pi(x)$) and degradation model ($\Pi(y|x)$), the posterior distribution reveals the likely and unlikely states of the “true” (unobserved) image X . Having constructed X to contain all relevant image attributes, such as locations of boundaries, labels of objects or textures, and so-on, the posterior distribution comes to play the fundamental role in our approach to image processing.

The posterior distribution is easily derived from “Bayes’ rule”

$$\Pi(x|y) = \frac{\Pi(y|x)\Pi(x)}{\Pi(y)}$$

The denominator, $\Pi(y)$, is difficult to evaluate. It derives from the prior and degradation models by integration: $\Pi(y) = \int_x \Pi(y|x)\Pi(dx)$, but the formula is computationally intractable. Happily, our analysis of the posterior distribution will require only *ratios*, not absolute probabilities. Since y is fixed by observation, $\frac{1}{\Pi(y)}$ is a constant that can be ignored (see paragraph below on “computing”).

As an example we consider the simple “Ising model” prior, with observations corrupted by additive white noise. Then

$$\Pi(x) = \frac{1}{z} \exp\left\{-\beta \sum_{(s,t)} x_s x_t\right\}$$

and

$$\Pi(\mathbf{y}|\mathbf{x}) = \left(\frac{1}{2\pi\sigma^2}\right)^{\frac{|S|}{2}} \exp\left\{-\frac{1}{2\sigma^2} \sum_{s \in S} (y_s - x_s)^2\right\}$$

The posterior distribution is then

$$\Pi(\mathbf{x}|\mathbf{y}) = \frac{1}{z_p} \exp\left\{-\beta \sum_{(s,t)} x_s x_t - \frac{1}{2\sigma^2} \sum_{s \in S} (y_s - x_s)^2\right\}$$

We denote by z_p the normalizing constant for the posterior distribution. Of course, it depends upon \mathbf{y} , but the latter is fixed. Notice that the posterior distribution is again a MRF. In the case of additive white noise, the neighborhood system of the posterior distribution is that of the prior, and hence local. For a wide class of useful degradation models, including combinations of blur, added or multiplicative “colored noise,” and a variety of nonlinear transformations, the posterior distribution is a MRF with a more or less local graph structure. This is convenient for our computational schemes, as we shall see shortly. We should note, however, that exceptions occur. In tomography, for example, the posterior distribution is associated with a highly non-local graph. This situation incurs a high computational cost (see [5] for more details).

2.4 MAP Estimate.

In our framework, image processing amounts to choosing a particular image \mathbf{x} , given an observation $Y = \mathbf{y}$. A sensible, and suitably-defined optimal, choice is the “maximum a posteriori,” or “MAP” estimate:

$$\text{choose } \mathbf{x} \text{ to maximize } \Pi(\mathbf{x}|\mathbf{y})$$

The MAP estimate chooses the most likely \mathbf{x} , given the observation. In most applications, our goal is to identify the MAP estimate, or a suitable approximation. However, in some settings other estimators are more appropriate. We have found, for example, that the posterior mean ($\int \mathbf{x} \Pi(d\mathbf{x}|\mathbf{y})$) is more effective for tomography, at least in our experiments. Here, we concentrate on MAP estimation.

In most applications we can not hope to identify the true maximum a posteriori image vector \mathbf{x} . To appreciate the computational difficulty, consider again the Ising model with added white noise:

$$(2.3) \quad \Pi(\mathbf{x}|\mathbf{y}) = \frac{1}{z_p} \exp\left\{-\beta \sum_{(s,t)} x_s x_t - \frac{1}{2\sigma^2} \sum_{s \in S} (y_s - x_s)^2\right\}$$

This is to be maximized over all possible vectors $x = \{x_s\}_{s \in S} \in \{-1, 1\}^{|S|}$. With $S \sim 10^5$, brute force approaches are intractable; instead, we will employ a Monte Carlo algorithm which gives adequate approximations.

Maximizing (2.3) amounts to minimizing

$$U_p(x) = -\beta \sum_{(s,t)} x_s x_t - \frac{1}{2\sigma^2} \sum_{s \in S} (y_s - x_s)^2$$

which might be thought of as the “posterior energy”. (As with z_p , the fixed observation y is suppressed in the notation $U_p(x)$.) More generally, we write the posterior distribution as

$$(2.4) \quad \frac{1}{z_p} \exp\{-U_p(x)\}$$

and characterize the MAP estimator as the solution to the problem

$$\text{choose } x \text{ to minimize } U_p(x)$$

The utility of this point of view is that it suggests a further analogy to statistical mechanics, and a computation scheme for approximating the MAP estimate, which we shall now describe.

2.5 Computing.

Pretend that (2.4) is the equilibrium Gibbs distribution of a real system. Recall that MAP estimation amounts to finding a minimal energy state. For many physical systems the low energy states are the most ordered, and these often have desirable properties. The state of silicon suitable for wafer manufacturing, for example, is a low energy state. Physical chemists achieve low energy states by heating and then slowly cooling a substance. This procedure is called *annealing*. Cerný [1] and Kirkpatrick [12] suggest searching for good minimizers of $U(\cdot)$ by *simulating* the dynamics of annealing, with U playing the role of energy for an (imagined) physical system. In our image processing experiments, we often use “simulated annealing” to find an approximation to the MAP estimator.

Dynamics are simulated by producing a Markov chain, $X(1), X(2), \dots$ with transition probabilities chosen so that the equilibrium distribution is the posterior (Gibbs) distribution (2.4). One way to do this is with the “Metropolis algorithm” [14]. More convenient for image processing is a variation we call *stochastic relaxation*. The full story can be found in [4] and [9]. Briefly, in stochastic relaxation we choose a sequence of sites

$s(1), s(2), \dots \in S$ such that each site in S is "visited" infinitely often. If $X(t) = x$, say, then $X_r(t+1) = x_r \forall r \neq s(t), r \in S$, and $X_{s(t)}(t+1)$ is a sample from

$$\Pi(X_{s(t)} = \cdot | X_r = x_r, r \neq s(t)),$$

the conditional distribution on $X_{s(t)}$ given $X_r = x_r \forall r \neq s(t)$. By the Markov property,

$$\Pi(X_{s(t)} = \cdot | X_r = x_r, r \neq s(t)) = \Pi(X_{s(t)} = \cdot | X_r = x_r, r \in G_{s(t)}^p)$$

where $\{G_s^p\}_{s \in S}$ is the *posterior* neighborhood system, determined by the posterior energy $U_p(\cdot)$. The prior distributions that we have experimented with have mostly had local neighborhood systems, and usually the posterior neighborhood system is also more or less local as well. This means that $|G_{s(t)}^p|$ is small, and this makes it relatively easy to generate, Monte Carlo, $X(t+1)$ from $X(t)$. In fact, if Ω is the range of $X_{s(t)}$, then

$$(2.5) \quad \Pi(X_{s(t)} = \alpha | X_r = x_r, r \in G_{s(t)}^p) = \frac{\Pi(\alpha, s(t)x)}{\sum_{\hat{\alpha} \in \Omega} \Pi(\hat{\alpha}, s(t)x)}$$

where

$$(\alpha, s(t)x)_r = \begin{cases} \alpha & \text{if } r = s(t) \\ x_r & \text{if } r \neq s(t) \end{cases}$$

Notice that (fortunately!) there is no need to compute the posterior partition function z_p . Also, the expression on the right hand side of (2.5) involves only those potential terms associated with cliques containing $s(t)$, since all other terms are the same in the numerator and the denominator.

To simulate annealing, we introduce an artificial "temperature" into the posterior distribution:

$$\Pi_T(x) = \frac{\exp\{-\frac{U_p(x)}{T}\}}{Z_p(T)}$$

As $T \rightarrow 0$, $\Pi_T(\cdot)$ concentrates on low energy states of U_p . To actually find these states, we run the stochastic relaxation algorithm while slowly lowering the temperature. Thus $T = T(t)$, and $T(t) \downarrow 0$. $\Pi_{T(t)}(\cdot)$ replaces $\Pi(\cdot)$ in computing the transition $X(t) \rightarrow X(t+1)$. In [4] we showed that, under suitable hypotheses on the sequence of site visits, $s(1), s(2), \dots$:

If $T(t) > \frac{c}{1+\log(1+t)}$, $T(t) \downarrow 0$, then for all c sufficiently large $X(t)$ converges weakly to the distribution concentrating uniformly on $\{x : U(x) = \min_y U(y)\}$.

More recently, our theorem has been improved upon by many authors. In particular, the smallest constant c which guarantees convergence of the annealing algorithm to a

global minimum can be specified in terms of the energy function U_p (see 6 and 10). Also, see Gidas [7] for some ideas about faster annealing via "renormalization group" methods.

In the experiments with FLIR images to be described here, MAP estimates are approximated by using the annealing algorithm. This involves Monte Carlo computer-generation of the sequence $X(1), X(2), \dots$, terminating when the state ceases to change substantially.

3 A GENERIC OBJECT/BACKGROUND MODEL.

The general modeling strategy described in Section 2 has been implemented for FLIR images with immediate objectives of image restoration (i) to "smooth" and enhance homogeneous subregions corresponding, for example, to an object or to a large component of an object of interest, and (ii) to highlight boundaries between separate homogeneous subregions as a precursor to object detection and recognition. We have designed and implemented a two-level hierarchical MRF model combining the directly observable pixel process and a linked unobservable binary process indicating the presence or absence of edge elements. Models like the one described here were suggested and illustrated in [2].

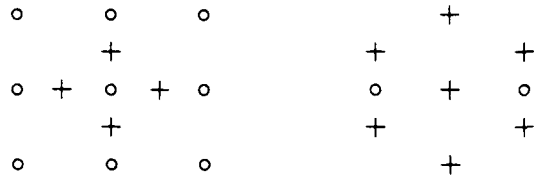
3.1 Scene Model.

The image process X comprises the pixel process X^P and the edge process X^E , $X = \{X^P, X^E\}$. As usual, the pixel sites form an $R \times C$ array of points (R rows and C columns) in a square lattice arrangement. We denote this $R \times C$ array by S^P . The sites for the edge process, collectively denoted S^E , also form a regular graph structure, envisioned as fitting between the sites in S^P . Let u, v denote pixel sites in the square lattice S^P . For each pair u, v of horizontally or vertically adjacent pixels, there exists an "edge site" denoted $\langle u, v \rangle$ in S^E . The edge site $s = \langle u, v \rangle$ corresponds to the location of possible edge or boundary element between pixels u and v . The edge variables are binary, with $X_{\langle u, v \rangle}^E$ equalling 1 or 0 to indicate the presence or absence of an edge element at $\langle u, v \rangle$. The process X^E consists of $R(C - 1) + C(R - 1)$ variables $X_{\langle u, v \rangle}^E$.

The totality of edge and pixel sites is denoted by S . (The generic point s may refer to a pixel or to an edge site $\langle u, v \rangle$.) The neighborhood system $G = \{G_s, s \in S\}$ governs the Markovian dependence structure of $X = \{X^P, X^E\}$. The size of the neighborhood determines the range of interactions. We restrict our design of the process to "small" or "local" neighborhood sets G_s , to keep the mathematical models as simple as possible and to assure feasibility of computational procedures.

We adopt the following neighborhood system. Each pixel site has eight pixel neighbors, the nearest ones, and four edge neighbors. Each edge site $\langle u, v \rangle$ has six edge neighbors—corresponding to possible continuations of a boundary from $\langle u, v \rangle$ —and the two pixel neighbors u and v . Sites near the boundary of the lattice have fewer neighbors. The canonical pixel neighborhood G_u and edge neighborhood $G_{\langle s, t \rangle}$ are depicted in the figure below, where circles represent pixels and pluses represent edge

sites. (We believe this edge graph originated in [11].)



To illustrate the functional form of the models, suppose first that we are only interested in modeling “smoothness” or “regularity” in the intensity array X^P , i.e., the tendency of nearby pixels to have similar intensities. Then a suitable model might be $X = X^P$ with

$$\Pi(X = x) = Z^{-1} \exp\left\{\theta \sum_{(s,t)} C_{(s,t)} \phi(x_s - x_t)\right\}.$$

where the sum extends over all neighboring pairs (s, t) of pixels. (Thus each interior pixel is included in eight terms in the summation.) Here $\phi = \phi(\delta)$ is an even function, decreasing for $\delta > 0$; θ is a parameter which corresponds to “inverse temperature” and it governs the degree of regularity. It is distinct from the “artificial temperature” T introduced for the annealing algorithm (Section 2.5). The coefficient $C_{(s,t)}$ is introduced to allow different weighting of pixel pairs oriented in different directions. We commonly fix $C_{(s,t)} = 1$ for the horizontal and vertical pairs and $C_{(s,t)} = 1/\sqrt{2}$ for diagonally adjacent pairs. A renormalization argument shows that this weighting is “asymptotically correct” in order for the discrete digital images X^P to approximate rotationally invariant (isotropic) images on a continuous background [8]. The weights also permit accurate modeling of anisotropic FLIR images.

A flexible and well-tested choice for ϕ is of the form

$$(3.1) \quad \phi(\delta) = \left(1 + \left|\frac{\delta}{B}\right|^2\right)^{-1}$$

where B is a parameter depending on the dynamic range of the image. An attractive feature of this ϕ -function—in contrast to one that decreases without bound—is that it *does not* attach ever increasing penalties to larger differences δ , and thus it will allow sharp gradients in intensity across region boundaries. A choice such as $\phi(\delta) = -\delta^2$ would *a priori* inhibit, indeed prohibit, adjacent, internally homogeneous subregions with highly separated intensities.

With the inclusion of the edge process X^E we incorporate our expectations about both the interactions between intensities and edges—i.e., where the edges belong—and about clusters of nearby edges. We are not exactly modeling entire boundaries with this

two-level model, but rather *segments* of boundaries; except in the simplest imagery and with larger neighborhoods, it is essentially impossible to distinguish actual boundary segments from intensity gradients due to lighting, texture, etc.

For the pixel-edge process, the complete energy function $U = U(X^P, X^E)$ is decomposed into two components:

$$U(X^P, X^E) = U^1(X^P, X^E) + U^2(X^E).$$

We construct U^1 so that the most likely configurations will have $X_{\langle s,t \rangle}^E = 1$ (respectively 0) when the intensity difference $|x_s^P - x_t^P|$ between neighboring pixels is large (resp. small). Put differently, we want to “break” the bond between pixels s and t when their values are “far” apart. Thus we choose

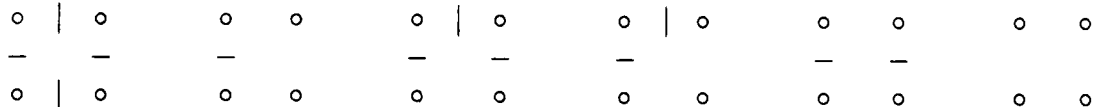
$$(3.2) \quad U^1(x^P, x^E) = - \sum_{(s,t)} \theta_1 C_{(s,t)} (\phi(x_s^P - x_t^P) - \theta_2) \times (1 - I_{(s,t)}(X^E))$$

where $\theta_1 > \theta_2 > 0$. The value of δ for which $\theta_1 C_{(s,t)} \phi(\delta) = \theta_2$ represents an intensity difference for which we have “no preference” in regard to the on-off state of an edge; such interpretations of the model parameters are helpful when one is setting or estimating values of the parameters. Finally, in equation (3.2), $I_{(s,t)}(X^E) = 1$ when the X^E process “breaks” the bond between pixels s and t , and $I_{(s,t)}(X^E) = 0$ otherwise. In particular, if s and t are horizontal or vertical neighbors, then $I_{(s,t)}(X^E) = X_{\langle s,t \rangle}^E$ and if s and t are diagonal neighbors, then $I_{(s,t)}(X^E)$ is a Boolean function of four edge elements between s and t requiring, for its value to be 1, that at least two of the edge elements are “on” and that they connect to form a segment separating s from t .

The remaining component U^2 of the total energy function governs the organization of nearby edges. We define

$$U^2(x^E) = -\theta_3 \sum_D V_D(x^E)$$

where $\theta_3 > 0$ and where the sum extends over all subsets D of four neighboring edge sites—the maximal “cliques” in the edge graph. The clique function V_D assigns weights in accordance with our expectations about edge behavior. More specifically, there are six possible clique states, up to rotational equivalence:



Here the bars indicate that the edge variable at the indicated site is “on”. Let $V_D = \xi_i$, for $i = 1, \dots, 6$, denote the weights assigned to the six configurations above. If we

assume that most pixels are not next to boundaries, that edges should continue, and that boundary congestion is unlikely, then we might choose $\xi_1 \leq \xi_2 \leq \xi_3 \leq \xi_4 \leq \xi_5 \leq \xi_6$. A specific image-dependent choice is made in the experiment described in Section 5.

One final point about the scene model: it is useful to write the total energy, up to an additive constant, as

$$(3.3) \quad -U(x) = \theta_1 \sum_{(s,t)} C_{(s,t)} \phi(x_s^P - x_t^P) (1 - I_{(s,t)}(x^E)) + \theta_2 \sum_{(s,t)} I_{(s,t)}(x^E) + \theta_3 \sum_D V_D(x^E)$$

For inferential purposes, this shows that our model is an *exponential family* in $\theta = (\theta_1, \theta_2, \theta_3)$. In addition, the form in (3.3) is useful for parameter interpretation; for instance, it becomes clear that θ_2 is a “reward” for edges.

3.2 Degradations.

The Gibbs distribution determined by the energy function U in equation (3.3) models the ideal scenes. There are several types of degradations that corrupt an ideal scene before it is observed. Most of these effects are well understood and can be modeled accurately in terms of the physical processes that underlie them. In the end, the first approximation of the degraded observed image Y will reduce to the pixel process X^P plus additive noise. The approximation is a gross simplification, even if it is reasonably effective as a basis for restoration algorithms. Ongoing research is exploring the use of more accurate degradation models which incorporate degradations modeled by convolutions; as we describe below, these latter degradations include atmospheric absorption and scattering, diffraction from geometric optics, and blurring from signal averaging and sampling by the IR sensor.

Two useful references for understanding degradations of IR images are the NV&EOL Technical Report [16] by J.A. Ratches et. al. and the NV&EOL internal working paper [15] prepared for our project by V. Mirelli. Some of the basic physics of IR radiation and detection is described in [17].

The primary sources of IR image degradation are:

- The actual thermal radiation from the ideal scene is random and additive to X^P . The random component has mean value 0 and has signal-dependent variance proportional to X^P . The exact distribution of the emitted radiation is well-modeled by a Poisson process and a Gaussian approximation is justified by convergence of the Poisson Law to the Normal.
- During atmospheric transmission of the radiation, there is absorption—dependent on air temperature and relative humidity—and scattering—dependent on visibility.

The scattering is normally modeled by Beer's Law [16]. The effects of absorption and scattering enter the mathematical model in the form of a convolution of the signal with a kernel depending on atmospheric parameters and range-to-target.

- At the sensor, the first degradation stems from optical diffraction. The geometrical optical effect is modeled by a convolution of the signal with a kernel depending on parameters of the optical system (lens diameter, focal lengths) and on the wavelength of the electromagnetic radiation.
- Black-body radiation from the positive temperature of the detector corrupts the image incident at the detector. This effect enters the model as additive "noise" on top of the signal.
- The electromagnetic energy in the IR radiation is converted to an electrical response by the sensor. The response is a random process subordinated on the input. This can be represented mathematically as signal-dependent additive noise, again with a Poisson distribution, where both the conditional mean and variance of the response (given the input) equals the input.
- The electrical response is digitized through a combination of averaging and sampling. Conceptually, a scanning detector returns a continuous response which is averaged in the direction of the scan and which is discretely sampled in the direction orthogonal to the scan. The combination of averaging and sampling implies that the observed process *will not* be isotropic. Digitization is described mathematically through a convolution of the continuous signal with a singular kernel.
- Finally, electronic noise may enter at the last stage of actually observing the digitized signal. The noise enters as an additive effect, independent of the signal.

4 IMPLEMENTATION OF THE RESTORATION ALGORITHM.

The following subsections give a complete listing of a standard FORTRAN77 program that implements stochastic relaxation, with optional annealing, for the model described in Section 3. The subroutine that computes the dependence of the total energy on the edge process (SUBROUTINE DEE) actually implements a model that is slightly more general than equation (3.3). It incorporates a parameter (CE2C) which inhibits the occurrence of nearby parallel edges. The model of Section 3 is implemented by this program when CE2C=0.

This program has been delivered to the Advanced Modeling Team at NV&EOL and has been used there for experiments with restoration of FLIR images. The presumptions about formats of input and output files are best documented by the input and output subroutines READIN and WRITEO, which are listed below. Experiments with the use of this program are described in Section 5.

4.1 Main Program RESTOR.

The main program guides input, output and stochastic relaxation of the pixel and edge processes.

```
PROGRAM RESTOR                                RES00010
C SET UP DATA STRUCTURES                      RES00020
  INCLUDE (COMMON)                             RES00030
C TYPES                                        RES00040
  INTEGER NIT                                  RES00050
C GET INPUT                                    RES00060
  CALL READIN                                  RES00070
C ITERATE                                       RES00080
  DO 10 NIT=NSTART,NSTOP                       RES00090
    PRINT *, 'ITERATION ', NIT                 RES00100
    IF (NIT.LE.NO) THEN                        RES00110
      T=TO                                       RES00120
    ELSE                                        RES00130
      T=TO/(1.0+LOG(FLOAT(NIT-NO)))           RES00140
    ENDIF                                       RES00150
    PRINT *, 'TEMPERATURE ', T                 RES00160
    IF (IXP.EQ.1) CALL ITXP                    RES00170
    IF (IXE.EQ.1) CALL ITXE                    RES00180
10  CONTINUE                                   RES00190
C OUTPUT RESULTS                               RES00200
```

CALL WRITEO
END

RES00210
RES00220

4.2 Include File COMMON.

The "include" file declares global variables, sets parameter values, and defines COMMON blocks.

CE1A is the model parameter θ_1 (equation 3.3).

CE1B is the model parameter B (equation 3.1).

CE2A is the model parameter θ_3 (equation 3.3).

CE2B is the model parameter θ_2 (equation 3.3).

CE2C is not used in model (3.3) and is set to 0.

PMIN is the minimum value of the range of the pixel process x_s^P .

PMAX is the maximum value of the range of the pixel process x_s^P .

SIGMA is the standard deviation of the additive noise corrupting the observed process Y .

MAXDA is the maximum number of equally spaced discrete levels used to quantize the range [PMIN,PMAX] of x_s^P .

NDA is the actual number of equally spaced discrete levels used to quantize the range [PMIN,PMAX] of x_s^P .

```
C CONSTANTS                                COM00010
  INTEGER NX, NY, MAXDA                     COM00020
  REAL DIAG                                  COM00030
  PARAMETER (NX=64,NY=64,MAXDA=100,DIAG=.707) COM00040
C DECLARE PARAMETERS, WHICH WILL BE READ FROM UNIT 7 COM00050
  REAL CE1A,CE1B,CE2A,CE2B,CE2C,PMIN,PMAX,SIGMA COM00060
C VARIABLES AND ARRAYS                      COM00070
  INTEGER IS, ID, IP, IXP, IXE, NO, NSTART, NSTOP, COM00080
  M      NDA                                  COM00090
  REAL TO,T,XP(O:NX+1,O:NY+1),XE(-1:NX+2,-1:NY+2,2),XPO(NX,NY), COM00100
  M      ADSIG,SIGSQD                         COM00110
  DOUBLEPRECISION SEED                      COM00120
C COMMON GLOBAL DATA STRUCTURES            COM00130
  COMMON SEED,CE1A,CE1B,CE2A,CE2B,CE2C,PMIN,PMAX,SIGMA, COM00140
  M      TO,T,XP,XE,XPO,ADSIG,SIGSQD,        COM00150
  M      IS,ID,IP,IXP,IXE,NO,NSTART,NSTOP,NDA COM00160
```


4.3 Subroutine READIN.

The input routine READIN prompts the user for interactive input of program and model parameters and reads in files containing images, including the observed image and any results that may be available from previous processing by the relaxation algorithm.

```

      SUBROUTINE READIN                                REA00010
C SET UP DATA STRUCTURES                            REA00020
      INCLUDE (COMMON)                                REA00030
C TYPES                                              REA00040
      INTEGER I, J, K                                REA00050
C EXTERNAL FUNCTIONS CALLED                          REA00060
      REAL GGUBFS                                     REA00070
C READ PARAMETER VALUES FROM UNIT 7                 REA00080
      READ(7,*), CE1A                                 REA00090
      READ(7,*), CE1B                                 REA00100
      READ(7,*), CE2A                                 REA00110
      READ(7,*), CE2B                                 REA00120
      READ(7,*), CE2C                                 REA00130
      READ(7,*), PMIN                                 REA00140
      READ(7,*), PMAX                                 REA00150
      READ(7,*), SIGMA                               REA00160
      CLOSE(UNIT=7)                                   REA00170
C DETERMINE IF GOAL IS IMAGE SAMPLING                REA00180
      IS=0                                            REA00190
      WRITE(6,*), 'ENTER 1 IF A SAMPLE IMAGE IS DESIRED, 0 IF PURPOSE' REA00200
      WRITE(6,*), 'IS RESTORATION'                  REA00210
      READ(6,*), IS                                   REA00220
C IF GOAL IS RESTORATION, DETERMINE IF ORIGINAL IMAGE IS RESULT OF REA00230
C A DEGRADATION
      ID=0                                            REA00240
      IF (IS.EQ.0) THEN                               REA00250
        WRITE(6,*), 'ENTER 1 IF THERE IS A DEGRADATION, 0 OTHERWISE' REA00260
        READ(6,*), ID                                REA00270
      ENDIF                                           REA00280
C DETERMINE IF IMAGE HAS ALREADY BEEN PARTIALLY PROCESSED REA00290
      IP=0                                            REA00300
      WRITE(6,*), 'ENTER 1 IF PROCESSING BEGAN WITH A PREVIOUS RUN,' REA00310
      WRITE(6,*), '0 OTHERWISE'                     REA00320
      READ(6,*), IP                                   REA00330
C DETERMINE WHICH LEVELS OF HIERARCHY ARE TO BE ACTIVE REA00340
      IXP=0                                           REA00350

```

IXE=0	REA00370
WRITE(6,*), 'ENTER 1 IF PIXEL PROCESS WILL BE ACTIVE, 0 OTHERWISE'	REA00380
READ(5,*), IXP	REA00390
WRITE(6,*), 'ENTER 1 IF EDGE PROCESS WILL BE ACTIVE, 0 OTHERWISE'	REA00400
READ(5,*) IXE	REA00410
C DETERMINE NUMBER OF DISCRETE VALUES	REA00420
WRITE(6,*), 'ENTER NUMBER OF GREY LEVELS'	REA00430
WRITE(6,*), '(NO MORE THAN',MAXDA,')'	REA00440
READ(5,*), NDA	REA00450
C DETERMINE TEMPERATURE CONTROL PARAMETERS	REA00460
WRITE(6,*), 'ENTER STARTING TEMPERATURE, EVEN IF'	REA00470
WRITE(6,*), 'THIS IS FROM A PREVIOUS RUN'	REA00480
READ(5,*), TO	REA00490
WRITE(6,*), 'ENTER NUMBER OF ITERATIONS BEFORE INITIATION'	REA00500
WRITE(6,*), 'OF ANNEALING'	REA00510
READ(5,*), NO	REA00520
C DETERMINE STARTING AND STOPPING ITERATIONS	REA00530
WRITE(6,*), 'ENTER NUMBER OF FIRST ITERATION FOR THIS RUN'	REA00540
READ(5,*), NSTART	REA00550
WRITE(6,*), 'ENTER NUMBER OF LAST ITERATION FOR THIS RUN'	REA00560
READ(5,*), NSTOP	REA00570
C GET SEED FOR RANDOM NUMBER GENERATOR	REA00580
WRITE(6,*), 'ENTER SEED FOR RANDOM NUMBER GENERATOR'	REA00590
READ(5,*), SEED	REA00600
C IF GOAL IS RESTORATION, AND THERE IS A DEGRADATION, THEN	REA00610
C DETERMINE THE STANDARD ERROR OF ANY NOISE THAT HAS BEEN ADDED TO	REA00620
C THE IMAGE AND COMPUTE THE TOTAL SIGMA SQUARED ("SIGSQD")	REA00630
IF (IS.EQ.0.AND.ID.EQ.1) THEN	REA00640
WRITE(6,*), 'ENTER STANDARD ERROR OF ADDED NOISE (0 IF NO'	REA00650
WRITE(6,*), 'NOISE HAS BEEN INTRODUCED)'	REA00660
READ(5,*), ADSIG	REA00670
SIGSQD=ADSIG**2+SIGMA**2	REA00680
ENDIF	REA00690
C READ IN DATA	REA00700
IF (IP.EQ.1) THEN	REA00710
DO 1 J=1,NY	REA00720
READ(1,6) (XP(I,J),I=1,NX)	REA00730
1 CONTINUE	REA00740
DO 3 K=1,2	REA00750
DO 4 J=1,NY	REA00760
READ(1,6) (XE(I,J,K),I=1,NX)	REA00770

4	CONTINUE	REA00780
3	CONTINUE	REA00790
6	FORMAT(10F7.2)	REA00800
	CLOSE(UNIT=1)	REA00810
	ENDIF	REA00820
	IF (ID.EQ.1) THEN	REA00830
	DO 7 J=1,NY	REA00840
	READ(2,6) (XPO(I,J),I=1,NX)	REA00850
7	CONTINUE	REA00860
	CLOSE(UNIT=2)	REA00870
	ENDIF	REA00880
	IF (IS.EQ.0.AND.ID.EQ.0.AND.IP.EQ.0) THEN	REA00890
	DO 9 J=1,NY	REA00900
	READ(3,6) (XP(I,J),I=1,NX)	REA00910
9	CONTINUE	REA00920
	CLOSE(UNIT=3)	REA00930
	ENDIF	REA00940
	C INITIALIZE DATA ARRAYS. ALL NONPIXEL STRUCTURES ARE	REA00950
	C INITIALIZED TO "NOT PRESENT", UNLESS THERE WAS	REA00960
	C PREVIOUS PROCESSING.	REA00970
	IF (ID.EQ.1.AND.IP.EQ.0) THEN	REA00980
	DO 15 I=1,NX	REA00990
	DO 20 J=1,NY	REA01000
	XP(I,J)=XPO(I,J)	REA01010
20	CONTINUE	REA01020
15	CONTINUE	REA01030
	ENDIF	REA01040
	IF (IS.EQ.1.AND.IP.EQ.0) THEN	REA01050
	DO 60 I=1,NX	REA01060
	DO 70 J=1,NY	REA01070
	XP(I,J)=PMIN+(PMAX-PMIN)*GGUBFS(SEED)	REA01080
70	CONTINUE	REA01090
60	CONTINUE	REA01100
	ENDIF	REA01110
	IF (IP.EQ.0) THEN	REA01120
	DO 75 K=1,2	REA01130
	DO 80 J=1,NY	REA01140
	DO 90 I=1,NX	REA01150
	XE(I,J,K)=0.0	REA01160
90	CONTINUE	REA01170
80	CONTINUE	REA01180

75	CONTINUE	REA01190
	ENDIF	REA01200
	C INITIALIZE DUMMY BOUNDARIES	REA01210
	DO 100 J=0,NY+1	REA01220
	XP(O,J)=1000.0	REA01230
	XP(NX+1,J)=1000.0	REA01240
100	CONTINUE	REA01250
	DO 110 I=1,NX	REA01260
	XP(I,O)=1000.0	REA01270
	XP(I,NY+1)=1000.0	REA01280
110	CONTINUE	REA01290
	DO 120 I=-1,NX+2	REA01300
	XE(I,-1,1)=0.0	REA01310
	XE(I,-1,2)=0.0	REA01320
	XE(I,0,1)=0.0	REA01330
	XE(I,0,2)=0.0	REA01340
	XE(I,NY,2)=0.0	REA01350
	XE(I,NY+1,1)=0.0	REA01360
	XE(I,NY+1,2)=0.0	REA01370
	XE(I,NY+2,1)=0.0	REA01380
	XE(I,NY+2,2)=0.0	REA01390
120	CONTINUE	REA01400
	DO 130 J=-1,NY+2	REA01410
	XE(-1,J,1)=0.0	REA01420
	XE(-1,J,2)=0.0	REA01430
	XE(0,J,1)=0.0	REA01440
	XE(0,J,2)=0.0	REA01450
	XE(NX,J,2)=0.0	REA01460
	XE(NX+1,J,1)=0.0	REA01470
	XE(NX+1,J,2)=0.0	REA01480
	XE(NX+2,J,1)=0.0	REA01490
	XE(NX+2,J,2)=0.0	REA01500
130	CONTINUE	REA01510
	END	REA01520

4.4 Subroutine WRITEO.

The output routine WRITEO writes the output image file to the disk.

```

SUBROUTINE WRITEO
C SET UP DATA STRUCTURES
  INCLUDE (COMMON)
C TYPES
  INTEGER I, J, K
C WRITE OUTPUT TO UNIT 4
  DO 1 J=1,NY
    WRITE(4,6) (XP(I,J),I=1,NX)
1   CONTINUE
    DO 3 K=1,2
      DO 4 J=1,NY
        WRITE(4,6) (XE(I,J,K),I=1,NX)
4     CONTINUE
3     CONTINUE
6     FORMAT(10F7.2)
      CLOSE(UNIT=4)
      END
WRIO0010
WRIO0020
WRIO0030
WRIO0040
WRIO0050
WRIO0060
WRIO0070
WRIO0080
WRIO0090
WRIO0100
WRIO0110
WRIO0120
WRIO0130
WRIO0140
WRIO0150
WRIO0160
WRIO0170
```

4.5 Subroutine ITXP.

The subroutine ITXP guides the execution of the relaxation algorithm for the pixel process X^P .

```

SUBROUTINE ITXP                                ITX00010
C SET UP DATA STRUCTURES                      ITX00020
  INCLUDE (COMMON)                             ITX00030
C TYPES                                        ITX00040
  INTEGER I,J,K                                ITX00050
  REAL EP(MAXDA), SUM(MAXDA), TOT, EMIN, EMAX, NRAND ITX00060
C EXTERNAL FUNCTIONS CALLED                   ITX00070
  REAL GGUBFS                                  ITX00080
C ITERATE PIXEL VALUES                       ITX00090
  DO 10 J=1,NY                                 ITX00100
  DO 20 I=1,NX                                 ITX00110
C COMPUTE ENERGY VECTOR FOR PIXEL (I,J) AND STORE IN EP. EP(K) ITX00120
C IS THE RELATIVE ENERGY FOR XP(I,J) AT THE K'TH DISCRETE VALUE ITX00130
  CALL PIXEN(I,J,EP)                           ITX00140
C PREVENT OVERFLOWS AND UNDERFLOWS BY RESCALING AND TRUNCATING EP ITX00150
  EMIN =EP(1)                                  ITX00160
  DO 5 K=2,NDA                                  ITX00170
    IF (EP(K) .LT. EMIN) THEN                   ITX00180
      EMIN=EP(K)                                ITX00190
    ENDIF                                       ITX00200
5  CONTINUE                                     ITX00210
  EMAX=T*20.0                                  ITX00220
  DO 6 K=1,NDA                                  ITX00230
    EP(K)=MIN(EMAX,EP(K)-EMIN)                 ITX00240
6  CONTINUE                                     ITX00250
C UPDATE VALUE OF XP(I,J)                     ITX00260
  SUM(1)=EXP(-EP(1)/T)                         ITX00270
  DO 30 K=2,NDA                                 ITX00280
    SUM(K)=SUM(K-1)+EXP(-EP(K)/T)             ITX00290
30 CONTINUE                                     ITX00300
  NRAND=GGUBFS(SEED)                           ITX00310
  TOT=SUM(NDA)                                  ITX00320
  DO 40 K=1,NDA                                  ITX00330
    IF (NRAND .LE. (SUM(K)/TOT)) THEN          ITX00340
      XP(I,J)=PMIN+((PMAX-PMIN)*(K-1))/(NDA-1) ITX00350
      GO TO 20                                  ITX00360
    ENDIF                                       ITX00370

```

40 CONTINUE
20 CONTINUE
10 CONTINUE
END

ITX00380
ITX00390
ITX00400
ITX00410

4.6 Subroutine PIXEN.

The subroutine PIXEN is called by ITXP and returns the vector of (relative) energies that determine the local conditional distribution of the possible values for the pixel process at an arbitrary site.

```
C PIXEN(I,J,EP) COMPUTES THE RELATIVE ENERGY FOR THE NDA DIFFERENT      PIX00010
C POSSIBLE LEVELS OF PIXEL (I,J). THESE ARE RETURNED VIA EP(MAXDA).      PIX00020
      SUBROUTINE PIXEN(I,J,EP)                                           PIX00030
C SET UP DATA STRUCTURES                                               PIX00040
      INCLUDE (COMMON)                                                  PIX00050
C TYPES                                                                    PIX00060
      INTEGER I, J, K                                                  PIX00070
      REAL EP(MAXDA), ADIFF, XPTMP, INC                                PIX00080
C INITIALIZE EP                                                            PIX00090
      DO 10 K=1,NDA                                                    PIX00100
          EP(K)=0.0                                                    PIX00110
10    CONTINUE                                                         PIX00120
C COMPUTE DEGRADATION CONTRIBUTION TO ENERGY (IF ANY)                  PIX00130
      IF (ID.EQ.1) THEN                                                PIX00140
          CALL PIXENO(I,J,EP)                                          PIX00150
      ENDIF                                                            PIX00160
C COMPUTE PURE PIXEL CONTRIBUTION TO ENERGY                             PIX00170
      INC=(PMAX-PMIN)/(NDA-1)                                          PIX00180
      DO 20 K=1,NDA                                                    PIX00190
          XPTMP=PMIN+INC*(K-1)                                         PIX00200
C PIXEL TO UPPER LEFT:                                                  PIX00210
      IF ((XE(I-1,J,1)+XE(I-1,J-1,2))*                                PIX00220
M      (XE(I-1,J-1,1)+XE(I,J-1,2)).LT..5) THEN                       PIX00230
          ADIFF=ABS((XPTMP-XP(I-1,J-1))/CE1B)                          PIX00240
          EP(K)=EP(K)-CE1A*DIAG/(1.0+ADIFF*ADIFF)                     PIX00250
      ENDIF                                                            PIX00260
C PIXEL ABOVE:                                                           PIX00270
      IF (XE(I,J-1,2).LE..5) THEN                                       PIX00280
          ADIFF=ABS((XPTMP-XP(I,J-1))/CE1B)                            PIX00290
          EP(K)=EP(K)-CE1A/(1.0+ADIFF*ADIFF)                           PIX00300
      ENDIF                                                            PIX00310
C PIXEL TO UPPER RIGHT:                                                 PIX00320
      IF ((XE(I,J-1,2)+XE(I,J-1,1))*                                PIX00330
M      (XE(I,J,1)+XE(I+1,J-1,2)).LT..5) THEN                       PIX00340
          ADIFF=ABS((XPTMP-XP(I+1,J-1))/CE1B)                          PIX00350
          EP(K)=EP(K)-CE1A*DIAG/(1.0+ADIFF*ADIFF)                     PIX00360
```


ENDIF	PIX00370
C PIXEL TO LEFT:	PIX00380
IF (XE(I-1,J,1).LE..5) THEN	PIX00390
ADIFF=ABS((XPTEMP-XP(I-1,J))/CE1B)	PIX00400
EP(K)=EP(K)-CE1A/(1.0+ADIFF*ADIFF)	PIX00410
ENDIF	PIX00420
C PIXEL TO RIGHT:	PIX00430
IF (XE(I,J,1).LE..5) THEN	PIX00440
ADIFF=ABS((XPTEMP-XP(I+1,J))/CE1B)	PIX00450
EP(K)=EP(K)-CE1A/(1.0+ADIFF*ADIFF)	PIX00460
ENDIF	PIX00470
C PIXEL TO LOWER LEFT:	PIX00480
IF ((XE(I-1,J,2)+XE(I-1,J,1))*	PIX00490
M (XE(I-1,J+1,1)+XE(I,J,2)).LT..5) THEN	PIX00500
ADIFF=ABS((XPTEMP-XP(I-1,J+1))/CE1B)	PIX00510
EP(K)=EP(K)-CE1A*DIAG/(1.0+ADIFF*ADIFF)	PIX00520
ENDIF	PIX00530
C PIXEL BELOW:	PIX00540
IF (XE(I,J,2).LE..5) THEN	PIX00550
ADIFF=ABS((XPTEMP-XP(I,J+1))/CE1B)	PIX00560
EP(K)=EP(K)-CE1A/(1.0+ADIFF*ADIFF)	PIX00570
ENDIF	PIX00580
C PIXEL TO LOWER RIGHT:	PIX00590
IF ((XE(I,J,2)+XE(I,J+1,1))*	PIX00600
M (XE(I,J,1)+XE(I+1,J,2)).LT..5) THEN	PIX00610
ADIFF=ABS((XPTEMP-XP(I+1,J+1))/CE1B)	PIX00620
EP(K)=EP(K)-CE1A*DIAG/(1.0+ADIFF*ADIFF)	PIX00630
ENDIF	PIX00640
20 CONTINUE	PIX00650
END	PIX00660

4.7 Subroutine PIXENO.

The subroutine PIXENO is called by PIXEN and returns that part of the local energy vector attributable to the difference between the observed image and the current state of the restoration.

```
C PIXENO(I,J,EP) COMPUTES THE DEGRADATION CONTRIBUTION TO      PIX00010
C THE RELATIVE ENERGY FOR THE NDA DIFFERENT POSSIBLE LEVELS  PIX00020
C OF PIXEL (I,J). THESE ARE RETURNED VIA EP(MAXDA).          PIX00030
      SUBROUTINE PIXENO(I,J,EP)                                PIX00040
C SET UP DATA STRUCTURES                                     PIX00050
      INCLUDE (COMMON)                                       PIX00060
C TYPES                                                       PIX00070
      INTEGER I, J, K                                       PIX00080
      REAL EP(MAXDA), XPTMP, INC, TSIGSQ                    PIX00090
C COMPUTE DEGRADATION CONTRIBUTION TO ENERGY                PIX00100
      INC=(PMAX-PMIN)/(NDA-1)                                PIX00110
      TSIGSQ=2*SIGSQD                                         PIX00120
      DO 10 K=1,NDA                                          PIX00130
          XPTMP=PMIN+INC*(K-1)                                PIX00140
          EP(K)=EP(K)+(XPTMP-XPO(I,J))**2/TSIGSQ             PIX00150
10      CONTINUE                                             PIX00160
      END                                                    PIX00170
```

4.8 Subroutine ITXE.

The subroutine ITXE guides the execution of the relaxation algorithm for the edge process X^E .

```

SUBROUTINE ITXE                                ITX00010
C SET UP DATA STRUCTURES                      ITX00020
  INCLUDE (COMMON)                            ITX00030
C TYPES                                        ITX00040
  INTEGER I, J, K                             ITX00050
  REAL PON, EXPO                               ITX00060
C EXTERNAL FUNCTIONS CALLED                  ITX00070
  REAL DEE                                     ITX00080
C ITERATE EDGE PROCESS                       ITX00090
  DO 10 K=1,2                                  ITX00100
  DO 20 J=1,NY+1-K                            ITX00110
  DO 30 I=1,NX-2+K                            ITX00120
    EXPO=MIN(10.0,MAX(-10.0,DEE(I,J,K)/T))    ITX00130
    PON=1/(1+EXP(EXPO))                       ITX00140
    IF (GGUBFS(SEED).LE.PON) THEN            ITX00150
      XE(I,J,K)=1.0                          ITX00160
    ELSE                                      ITX00170
      XE(I,J,K)=0.0                          ITX00180
    ENDIF                                     ITX00190
  CONTINUE                                    ITX00200
  CONTINUE                                    ITX00210
  CONTINUE                                    ITX00220
END                                            ITX00230

```

4.9 Subroutine DEE.

The subroutine DEE is called by ITXE and computes the energy difference between the states "on" and "off" for the edge element at an arbitrary edge site.

```
C DEE CALCULATES THE ENERGY DIFFERENCE (DELTA ENERGY) BETWEEN          DEE00010
C EDGE ELEMENT (I,J,K) IN STATE 1 (ON) AND EDGE ELEMENT (I,J,K)          DEE00020
C IN STATE 0 (OFF).                                                       DEE00030
    REAL FUNCTION DEE(I,J,K)                                               DEE00040
C SET UP DATA STRUCTURES                                                DEE00050
    INCLUDE (COMMON)                                                       DEE00060
C TYPES                                                                     DEE00070
    INTEGER I, J, K, NON                                                  DEE00080
    REAL HOLD, RON, ADIFF                                                 DEE00090
C INITIALIZE DEE                                                           DEE00100
    DEE=0.0                                                                DEE00110
C COMPUTE NONDIAGONAL PIXEL/EDGE CONTRIBUTION                             DEE00120
    ADIFF=ABS((XP(I,J)-XP(I+2-K,J+K-1))/CE1B)                             DEE00130
    DEE=DEE+CE1A/(1.0+ADIFF*ADIFF)                                         DEE00140
C COMPUTE NONDIAGONAL "BOND-BREAKING" PENALTY                             DEE00150
    DEE=DEE-CE2B                                                           DEE00160
C COMPUTE 4-CLIQUE TERMS, INCLUDING DIAGONAL PIXEL/EDGE                 DEE00170
C TERMS AND DIAGONAL BOND-BREAKING TERMS                                 DEE00180
    HOLD=XE(I,J,K)                                                         DEE00190
    XE(I,J,K)=1.0                                                          DEE00200
    IF (K.EQ.1.AND.J.GT.1) THEN                                           DEE00210
        RON=XE(I,J-1,1)+XE(I+1,J-1,2)+XE(I,J,1)+XE(I,J-1,2)           DEE00220
        NON=NINT(RON)                                                      DEE00230
        IF (NON.EQ.1) THEN                                                 DEE00240
            DEE=DEE+3*CE2A                                                 DEE00250
        ELSEIF (NON.EQ.2) THEN                                             DEE00260
            DEE=DEE-2*CE2A                                                 DEE00270
            IF (XE(I,J-1,2).GT..5) THEN                                    DEE00280
                DEE=DEE-CE2B                                               DEE00290
                ADIFF=ABS((XP(I,J)-XP(I+1,J-1))/CE1B)                   DEE00300
                DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)                       DEE00310
            ELSEIF (XE(I+1,J-1,2).GT..5) THEN                              DEE00320
                DEE=DEE-CE2B                                               DEE00330
                ADIFF=ABS((XP(I,J-1)-XP(I+1,J))/CE1B)                   DEE00340
                DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)                       DEE00350
            ELSE                                                            DEE00360
                DEE=DEE-2*CE2B                                             DEE00370
```

ADIFF=ABS((XP(I,J)-XP(I+1,J-1))/CE1B)	DEE00380
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00390
ADIFF=ABS((XP(I,J-1)-XP(I+1,J))/CE1B)	DEE00400
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00410
ENDIF	DEE00420
ELSEIF (NON.EQ.3) THEN	DEE00430
DEE=DEE+CE2A	DEE00440
IF (XE(I+1,J-1,2).LT..5) THEN	DEE00450
DEE=DEE-CE2B	DEE00460
ADIFF=ABS((XP(I,J)-XP(I+1,J-1))/CE1B)	DEE00470
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00480
ELSEIF (XE(I,J-1,2).LT..5) THEN	DEE00490
DEE=DEE-CE2B	DEE00500
ADIFF=ABS((XP(I,J-1)-XP(I+1,J))/CE1B)	DEE00510
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00520
ENDIF	DEE00530
ELSEIF (NON.EQ.4) THEN	DEE00540
DEE=DEE+CE2A	DEE00550
ENDIF	DEE00560
ENDIF	DEE00570
IF (K.EQ.1.AND.J.LT.NY) THEN	DEE00580
RON=XE(I,J,1)+XE(I+1,J,2)+XE(I,J+1,1)+XE(I,J,2)	DEE00590
NON=NINT(RON)	DEE00600
IF (NON.EQ.1) THEN	DEE00610
DEE=DEE+3*CE2A	DEE00620
ELSEIF (NON.EQ.2) THEN	DEE00630
DEE=DEE-2*CE2A	DEE00640
IF (XE(I,J,2).GT..5) THEN	DEE00650
DEE=DEE-CE2B	DEE00660
ADIFF=ABS((XP(I,J)-XP(I+1,J+1))/CE1B)	DEE00670
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00680
ELSEIF (XE(I+1,J,2).GT..5) THEN	DEE00690
DEE=DEE-CE2B	DEE00700
ADIFF=ABS((XP(I,J+1)-XP(I+1,J))/CE1B)	DEE00710
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00720
ELSE	DEE00730
DEE=DEE-2*CE2B	DEE00740
ADIFF=ABS((XP(I,J)-XP(I+1,J+1))/CE1B)	DEE00750
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00760
ADIFF=ABS((XP(I,J+1)-XP(I+1,J))/CE1B)	DEE00770
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEE00780

ENDIF	DEEO0790
ELSEIF (NON.EQ.3) THEN	DEEO0800
DEE=DEE+CE2A	DEEO0810
IF (XE(I+1,J,2).LT..5) THEN	DEEO0820
DEE=DEE-CE2B	DEEO0830
ADIFF=ABS((XP(I,J)-XP(I+1,J+1))/CE1B)	DEEO0840
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO0850
ELSEIF (XE(I,J,2).LT..5) THEN	DEEO0860
DEE=DEE-CE2B	DEEO0870
ADIFF=ABS((XP(I,J+1)-XP(I+1,J))/CE1B)	DEEO0880
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO0890
ENDIF	DEEO0900
ELSEIF (NON.EQ.4) THEN	DEEO0910
DEE=DEE+CE2A	DEEO0920
ENDIF	DEEO0930
ENDIF	DEEO0940
IF (K.EQ.2.AND.I.GT.1) THEN	DEEO0950
RON=XE(I-1,J,1)+XE(I,J,2)+XE(I-1,J+1,1)+XE(I-1,J,2)	DEEO0960
NON=NINT(RON)	DEEO0970
IF (NON.EQ.1) THEN	DEEO0980
DEE=DEE+3*CE2A	DEEO0990
ELSEIF (NON.EQ.2) THEN	DEEO1000
DEE=DEE-2*CE2A	DEEO1010
IF (XE(I-1,J,1).GT..5) THEN	DEEO1020
DEE=DEE-CE2B	DEEO1030
ADIFF=ABS((XP(I,J)-XP(I-1,J+1))/CE1B)	DEEO1040
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1050
ELSEIF (XE(I-1,J+1,1).GT..5) THEN	DEEO1060
DEE=DEE-CE2B	DEEO1070
ADIFF=ABS((XP(I-1,J)-XP(I,J+1))/CE1B)	DEEO1080
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1090
ELSE	DEEO1100
DEE=DEE-2*CE2B	DEEO1110
ADIFF=ABS((XP(I,J)-XP(I-1,J+1))/CE1B)	DEEO1120
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1130
ADIFF=ABS((XP(I-1,J)-XP(I,J+1))/CE1B)	DEEO1140
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1150
ENDIF	DEEO1160
ELSEIF (NON.EQ.3) THEN	DEEO1170
DEE=DEE+CE2A	DEEO1180
IF (XE(I-1,J+1,1).LT..5) THEN	DEEO1190

DEE=DEE-CE2B	DEEO1200
ADIFF=ABS((XP(I,J)-XP(I-1,J+1))/CE1B)	DEEO1210
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1220
ELSEIF (XE(I-1,J,1).LT..5) THEN	DEEO1230
DEE=DEE-CE2B	DEEO1240
ADIFF=ABS((XP(I-1,J)-XP(I,J+1))/CE1B)	DEEO1250
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1260
ENDIF	DEEO1270
ELSEIF (NON.EQ.4) THEN	DEEO1280
DEE=DEE+CE2A	DEEO1290
ENDIF	DEEO1300
ENDIF	DEEO1310
IF (K.EQ.2.AND.I.LT.NX) THEN	DEEO1320
RON=XE(I,J,1)+XE(I+1,J,2)+XE(I,J+1,1)+XE(I,J,2)	DEEO1330
NON=NINT(RON)	DEEO1340
IF (NON.EQ.1) THEN	DEEO1350
DEE=DEE+3*CE2A	DEEO1360
ELSEIF (NON.EQ.2) THEN	DEEO1370
DEE=DEE-2*CE2A	DEEO1380
IF (XE(I,J,1).GT..5) THEN	DEEO1390
DEE=DEE-CE2B	DEEO1400
ADIFF=ABS((XP(I,J)-XP(I+1,J+1))/CE1B)	DEEO1410
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1420
ELSEIF (XE(I,J+1,1).GT..5) THEN	DEEO1430
DEE=DEE-CE2B	DEEO1440
ADIFF=ABS((XP(I,J+1)-XP(I+1,J))/CE1B)	DEEO1450
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1460
ELSE	DEEO1470
DEE=DEE-2*CE2B	DEEO1480
ADIFF=ABS((XP(I,J)-XP(I+1,J+1))/CE1B)	DEEO1490
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1500
ADIFF=ABS((XP(I,J+1)-XP(I+1,J))/CE1B)	DEEO1510
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1520
ENDIF	DEEO1530
ELSEIF (NON.EQ.3) THEN	DEEO1540
DEE=DEE+CE2A	DEEO1550
IF (XE(I,J+1,1).LT..5) THEN	DEEO1560
DEE=DEE-CE2B	DEEO1570
ADIFF=ABS((XP(I,J)-XP(I+1,J+1))/CE1B)	DEEO1580
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DEEO1590
ELSEIF (XE(I,J,1).LT..5) THEN	DEEO1600

DEE=DEE-CE2B	DDEE01610
ADIFF=ABS((XP(I,J+1)-XP(I+1,J))/CE1B)	DDEE01620
DEE=DEE+CE1A*DIAG/(1.0+ADIFF*ADIFF)	DDEE01630
ENDIF	DDEE01640
ELSEIF (NON.EQ.4) THEN	DDEE01650
DEE=DEE+CE2A	DDEE01660
ENDIF	DDEE01670
ENDIF	DDEE01680
C CONTRIBUTION FORM INHIBITION OF PARALLEL LINES	DDEE01690
IF (K.EQ.1) THEN	DDEE01700
DEE=DEE+CE2C*(XE(I-2,J,1)+XE(I-1,J,1)+XE(I+1,J,1)+XE(I+2,J,1))	DDEE01710
ELSE	DDEE01720
DEE=DEE+CE2C*(XE(I,J-2,2)+XE(I,J-1,2)+XE(I,J+1,2)+XE(I,J+2,2))	DDEE01730
ENDIF	DDEE01740
XE(I,J,K)=HOLD	DDEE01750
END	DDEE01760

4.10 Function Subprogram GGUBFS.

The function subprogram GGUBFS is from the proprietary IMSL Library and is used to generate pseudorandom numbers that are independent and uniformly distributed on (0,1). *The listing below should not be reproduced nor incorporated in any programs other than the present one unless its use is licensed on the system on which such a program is being developed.*

```
C  IMSL ROUTINE NAME   - GGUBFS                               GGU00010
C                                                            GGU00020
C-----
C                                                            GGU00030
C                                                            GGU00040
C  COMPUTER           - IBM/SINGLE                            GGU00050
C                                                            GGU00060
C  LATEST REVISION    - JUNE 1, 1980                         GGU00070
C                                                            GGU00080
C  PURPOSE            - BASIC UNIFORM (0,1) RANDOM NUMBER   GGU00090
C                    - FUNCTION FORM OF GGUBS                GGU00100
C                                                            GGU00110
C  USAGE              - FUNCTION GGUBFS (DSEED)             GGU00120
C                                                            GGU00130
C  ARGUMENTS          GGUBFS - RESULTANT DEVIATE.           GGU00140
C                    DSEED  - INPUT/OUTPUT DOUBLE PRECISION GGU00150
C                        ASSIGNED AN INTEGER VALUE IN THE   GGU00160
C                        EXCLUSIVE RANGE (1.DO, 2147483647.DO). GGU00170
C                        DSEED IS REPLACED BY A NEW VALUE TO BE GGU00180
C                        USED IN A SUBSEQUENT CALL.          GGU00190
C                                                            GGU00200
C  PRECISION/HARDWARE - SINGLE/ALL                           GGU00210
C                                                            GGU00220
C  REQD. IMSL ROUTINES - NONE REQUIRED                         GGU00230
C                                                            GGU00240
C  NOTATION           - INFORMATION ON SPECIAL NOTATION AND  GGU00250
C                    CONVENTIONS IS AVAILABLE IN THE MANUAL GGU00260
C                    INTRODUCTION OR THROUGH IMSL ROUTINE UHELP GGU00270
C                                                            GGU00280
C  COPYRIGHT          - 1978 BY IMSL, INC. ALL RIGHTS RESERVED. GGU00290
C                                                            GGU00300
C  WARRANTY           - IMSL WARRANTS ONLY THAT IMSL TESTING GGU00310
C                    APPLIED TO THIS CODE. NO OTHER WARRANTY, GGU00320
C                    EXPRESSED OR IMPLIED, IS APPLICABLE.   GGU00330
C                                                            GGU00340
```

C	-----	GGU00350
C		GGU00360
	REAL FUNCTION GGUBFS (DSEED)	GGU00370
C		GGU00380
	DOUBLE PRECISION DSEED	GGU00390
C		GGU00400
	DOUBLE PRECISION D2P31M,D2P31	GGU00410
C		GGU00420
	D2P31M=(2**31) - 1	GGU00430
C		GGU00440
	D2P31 =(2**31)(OR AN ADJUSTED VALUE)	GGU00450
	DATA D2P31M/2147483647.DO/	GGU00460
	DATA D2P31 /2147483648.DO/	GGU00470
C		GGU00480
	FIRST EXECUTABLE STATEMENT	GGU00490
	DSEED = DMOD(16807.DO*DSEED,D2P31M)	GGU00500
	GGUBFS = DSEED / D2P31	
	RETURN	
	END	

5 FLIR EXAMPLES.

The algorithm described in Sections 2 and 3 and implemented by the program of Section 4 has been applied to a variety of FLIR images provided by the Advanced Modeling Team at NV&EOL. The results of selected experiments are included here.

For these experiments, the model parameters were set on the basis of inspection of the digitized FLIR images to determine attributes such as dynamic range and noise-variance and on the basis of the insights and interpretations of the model parameters described in Section 3.

In each of the photographs in Appendix B, the upper-left panel contains a 32×32 section of the observed image. The upper-right panel contains the result of fifty iterations of the stochastic relaxation algorithm, with annealing. The lower-left panel contains the original observed image *plus additional noise* having standard deviation 8. The lower-right panel contains the result of fifty iterations of the stochastic relaxation algorithm, with annealing, applied to the noise corrupted image.

The model and program parameters for the experiments are given in the following table:

Model	Program	Value
θ_1	CE1A	10.4
B	CE1B	4.0
θ_2	CE2B	1.66
θ_3	CE2A	1.0
ξ_1		-4
ξ_2		-3
ξ_3		-2
ξ_4		-1
ξ_5		-1
ξ_6		0
	PMIN	40
	PMAX	238
	MAXDA	100
	NDA	100

For the original observed images, the standard deviation SIGMA of the additive noise presumed to be degrading the ideal image was set to 5.

For the images to which noise was added, the standard deviation in the restoration algorithm was set to $\sqrt{25 + 64} = 9.43$.

Eight figures are included in Appendix B.

6 REFERENCES.

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A COMPLEX SYSTEMS WORKING PAPERS.

During the course of the modeling project, a number of internal working papers were prepared describing progress and research plans for specific aspects of the research effort. These papers were not intended for general distribution. Nonetheless, because of the direct cooperation with the Advanced Modeling Team at NV&EOL, the working papers were all shared with the leaders of the team. Titles of the working papers directly related to the image analysis problems at NV&EOL include:

- An entropy approach to relaxation time, April 1983.
- Updating schemes for image processing, June 1983.
- Parameter estimation for some Markov random fields, August 1983.
- Synthesis of partition patterns, August 1983.
- Synthesis of surface patterns, August 1983.
- A computer experiment with sweep areas, October 1983.
- Some experiments with partition, shape, and network patterns, October 1983.
- Simulating cold patterns is difficult, November 1983.
- Stochastic relaxation for some continuous generator spaces, November 1983.
- Remarks on annealing schedules, December 1983.
- Recognizing objects, March 1984.
- Non-localized generators, May 1984.
- Parameter estimation for Markov random fields with hidden variables and experiments with the EM algorithm, August 1984.
- Aspects of image processing, September 1984.
- Software for image processing experiments, November 1984.
- Preliminaries to target identification in IR-pictures, April 1985.
- Recognizing patterns in the presence of nuisance parameters, February 1986.

- Modeling and recognition of textures, March 1986.
- Parallel logic under uncertainty, continued and applied to the car experiment, August 1986.

B. FIGURES

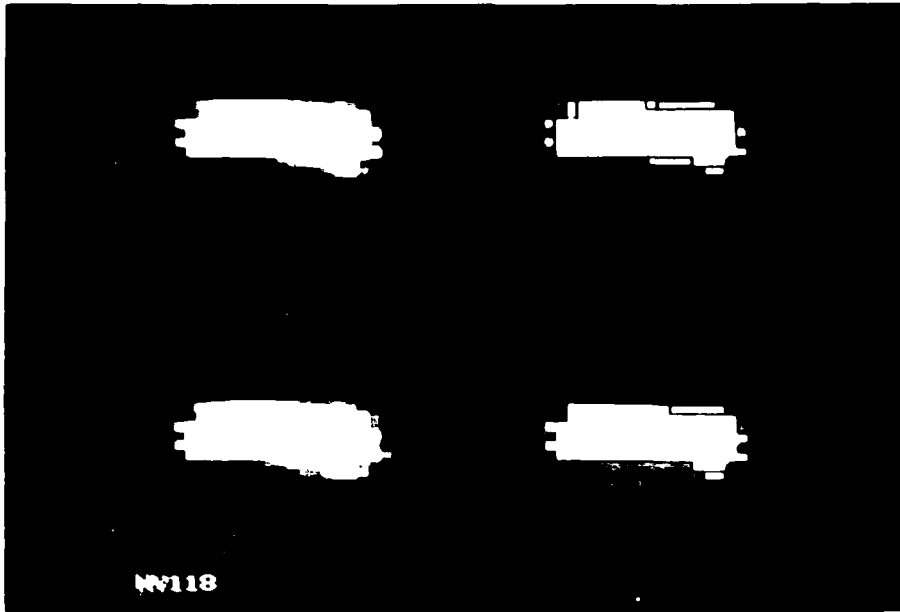


FIGURE 1

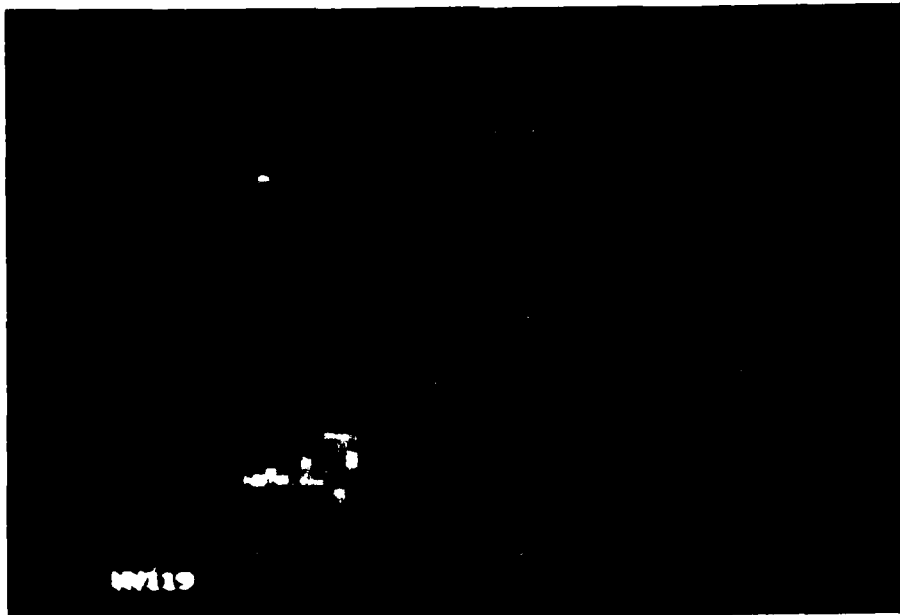


FIGURE 2

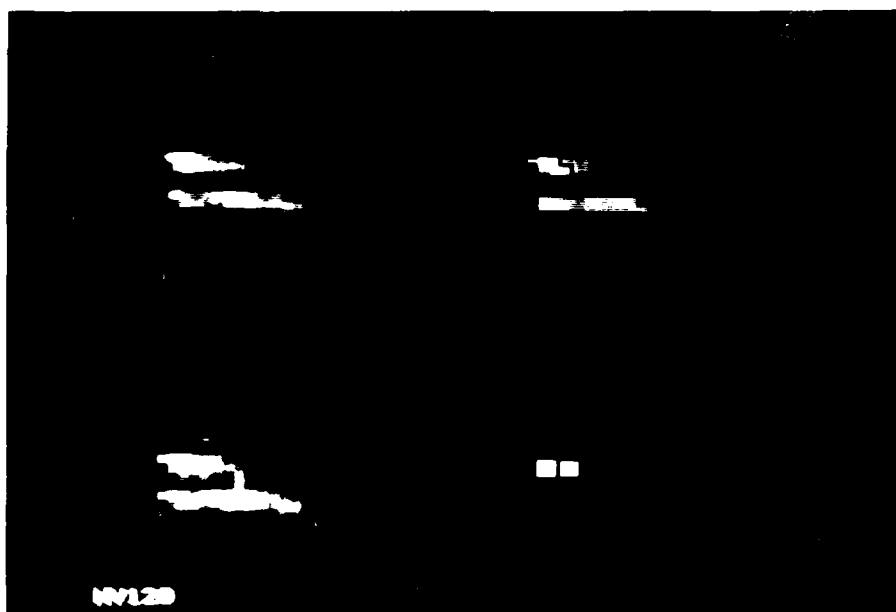


FIGURE 3

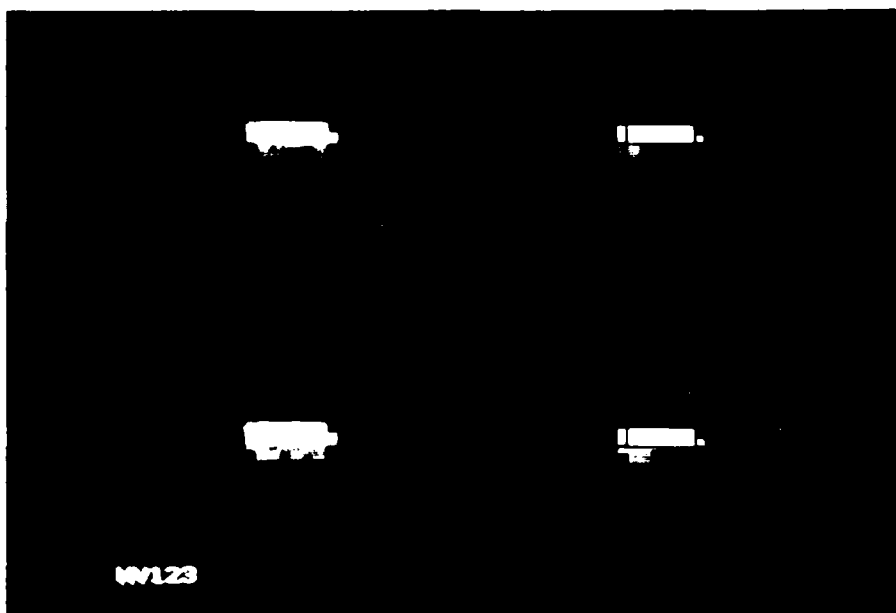


FIGURE 4

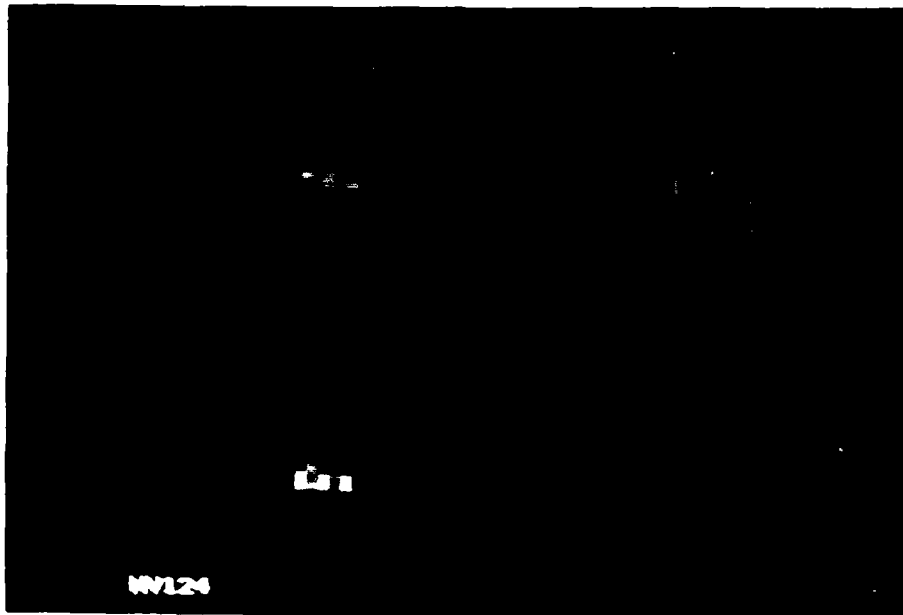


FIGURE 5

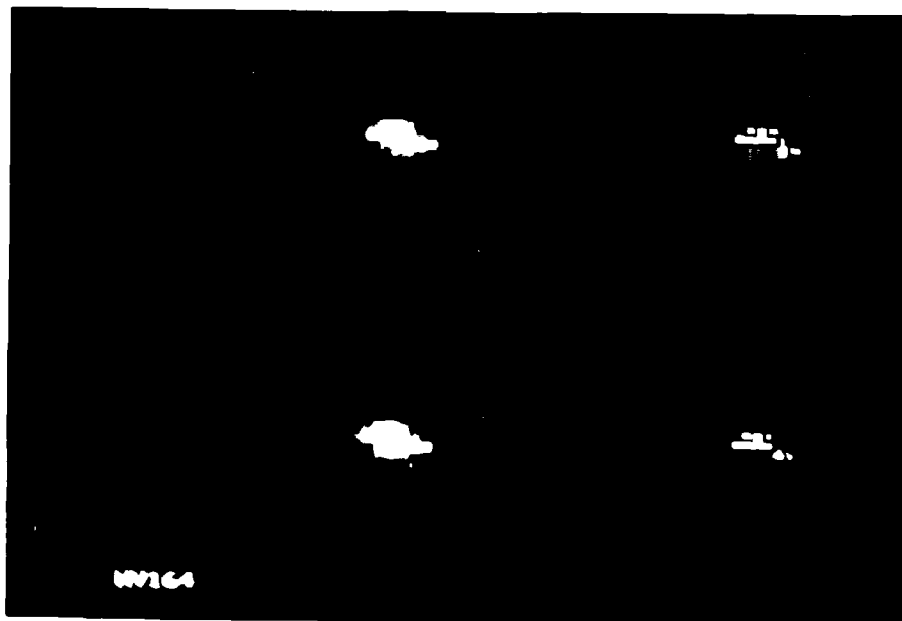


FIGURE 6

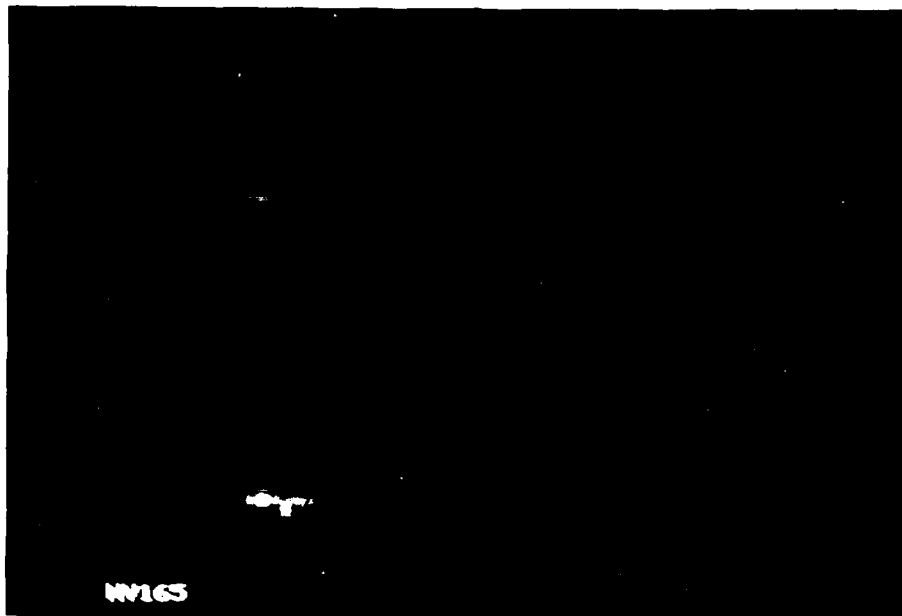


FIGURE 7

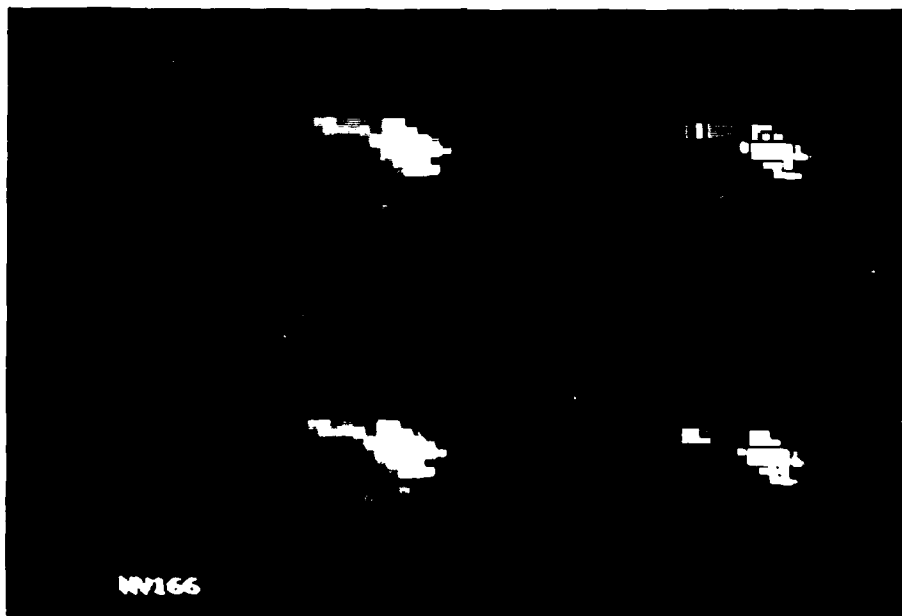


FIGURE 8

END

5-87

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